Power MOSFET

60 V, 11.5 m Ω , Single N-Channel, μ 8FL

Features

- Small Footprint (3.3x3.3 mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- AEC-Q101 Qualified
- These are Pb-Free Devices*

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	60	V
Gate-to-Source Voltage			V _{GS}	±20	V
Continuous Drain Cur-		T _{mb} = 25°C	I _D	29	Α
rent $R_{\Psi J-mb}$ (Notes 1, 2, 3, 4)	Steady	T _{mb} = 100°C		20	
Power Dissipation	State	T _{mb} = 25°C	P_{D}	21	W
R _{ΨJ-mb} (Notes 1, 2, 3)		T _{mb} = 100°C		10	
Continuous Drain Current R _{0.IA} (Notes 1 &		T _A = 25°C	I _D	11	Α
3, 4)	Steady State	T _A = 100°C		8.0	
Power Dissipation		T _A = 25°C	P_{D}	3.2	W
R _{θJA} (Notes 1, 3)		T _A = 100°C		1.6	
Pulsed Drain Current	$T_A = 25$	°C, t _p = 10 μs	I _{DM}	247	Α
Current limited by package T _A = 25°C (Note 4)			I _{DmaxPkg}	70	Α
Operating Junction and Storage Temperature			T _J , T _{stg}	-55 to 175	°C
Source Current (Body D	I _S	17	Α		
Single Pulse Drain-to-Source Avalanche Energy (T_J = 25°C, V_{DD} = 50 V, V_{GS} = 10 V, $I_{L(pk)}$ = 37 A, L = 0.1 mH, R_G = 25 Ω)			E _{AS}	48	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			T _L	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

Parameter	Symbol	Value	Unit
Junction-to-Mounting Board (top) - Steady State (Note 2, 3)	$R_{\Psi J-mb}$	7.3	°C/W
Junction-to-Ambient - Steady State (Note 3)	Rela	47	

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Psi (Ψ) is used as required per JESD51-12 for packages in which substantially less than 100% of the heat flows to single case surface.
- 3. Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

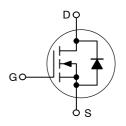


ON Semiconductor®

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V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX	
60 V	11.5 mΩ @ 10 V	29 A	
00 V	15 mΩ @ 4.5 V	297	

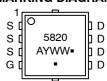
N-Channel





CASE 511AB

MARKING DIAGRAM



5820 = Specific Device Code A = Assembly Location

Y = Year
WW = Work Week
= Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NVTFS5820NLTAG	WDFN8 (Pb-Free)	1500/Tape & Reel
NVTFS5820NLTWG	WDFN8 (Pb-Free)	5000/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

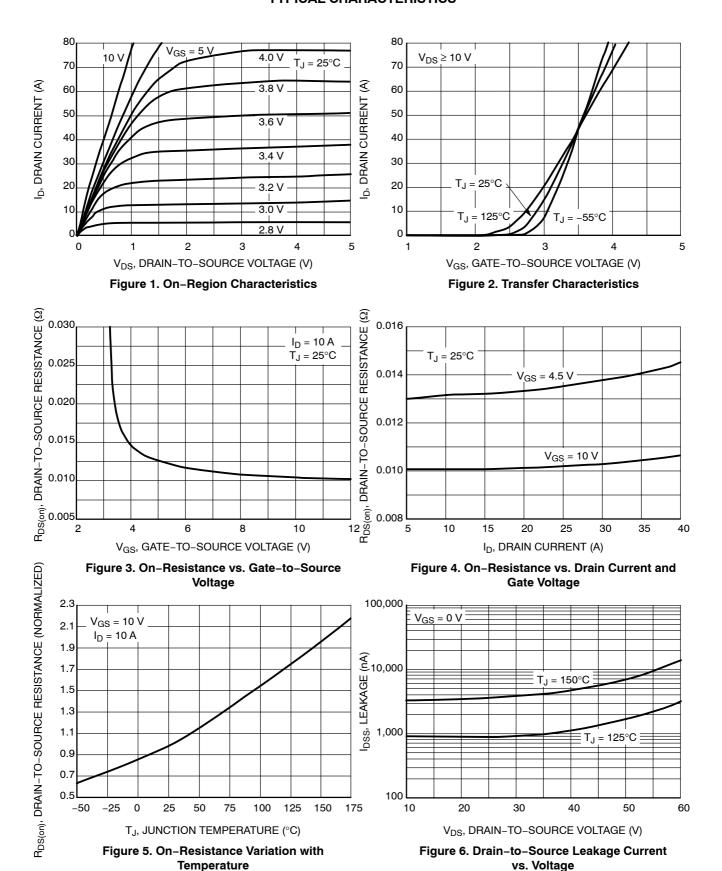
*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS			<u> </u>			-	
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		60			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				57		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25°C			1.0	μΑ
		$V_{DS} = 60 \text{ V}$	T _J = 125°C			10	
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} = ±20 V				±100	nA
ON CHARACTERISTICS (Note 5)			•		•	•	
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$	= 250 μA	1.5		2.3	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				6.2		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 8.7 A		10.1	11.5	mΩ
		V _{GS} = 4.5 V	I _D = 7.3 A		13.0	15	
Forward Transconductance	9FS	V _{DS} = 5 V, I _D = 10 A			24.6		S
CHARGES, CAPACITANCES AND GA	ATE RESISTAN	CE	•		-	-	•
Input Capacitance	C _{iss}				1462		pF
Output Capacitance	C _{oss}	V _{GS} = 0 V, f = 1.0 MH	Iz, V _{DS} = 25 V		150		1
Reverse Transfer Capacitance	C _{rss}				96		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 4	8 V, I _D = 10 A		28		nC
		V _{GS} = 4.5 V, V _{DS} = 4	8 V, I _D = 10 A		15		
Threshold Gate Charge	Q _{G(TH)}				1		
Gate-to-Source Charge	Q _{GS}		01/1 404		4		
Gate-to-Drain Charge	Q_{GD}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 4$	8 V, I _D = 10 A		8		
Plateau Voltage	V _{GP}		-		3		V
Gate Resistance	R _G				0.62		Ω
SWITCHING CHARACTERISTICS (No	ote 6)					-	
Turn-On Delay Time	t _{d(on)}				10		ns
Rise Time	t _r	$V_{GS} = 4.5 \text{ V}, V_{DS}$	s = 48 V,		28		
Turn-Off Delay Time	t _{d(off)}	$I_D = 10 \text{ A}, R_G = 2.5 \Omega$			19		1
Fall Time	t _f				22		
DRAIN-SOURCE DIODE CHARACTE	RISTICS		•				
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V, I _S = 10 A	T _J = 25°C		0.79	1.2	V
			T _J = 125°C		0.65		
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, } d_{IS}/d_t = 100 \text{ A/}\mu\text{s,}$ $I_S = 10 \text{ A}$			19		ns
Charge Time	t _a				13		
Discharge Time	t _b				6		
Reverse Recovery Charge	Q _{RR}				15		nC

^{5.} Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS

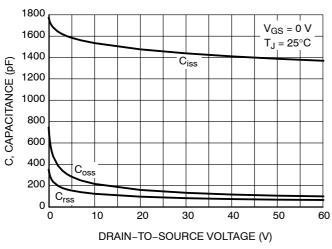


Figure 7. Capacitance Variation

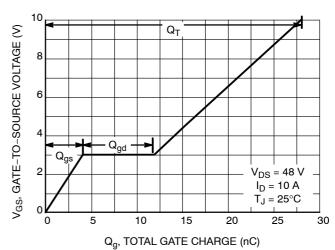


Figure 8. Gate-to-Source Voltage vs. Total Charge

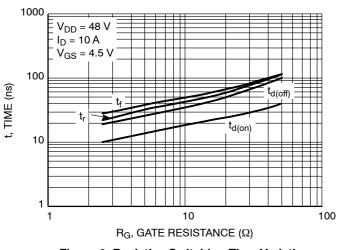


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

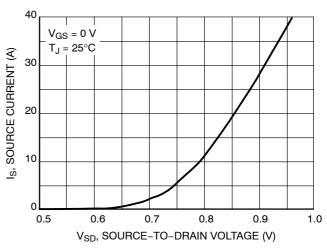


Figure 10. Diode Forward Voltage vs. Current

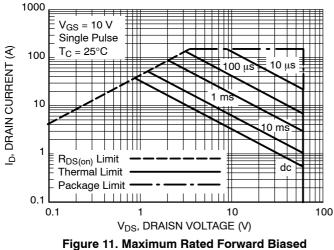


Figure 11. Maximum Rated Forward Biased
Safe Operating Area

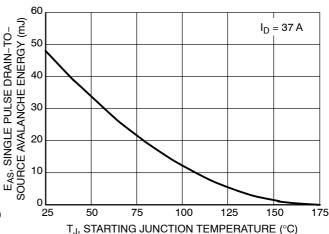


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL CHARACTERISTICS

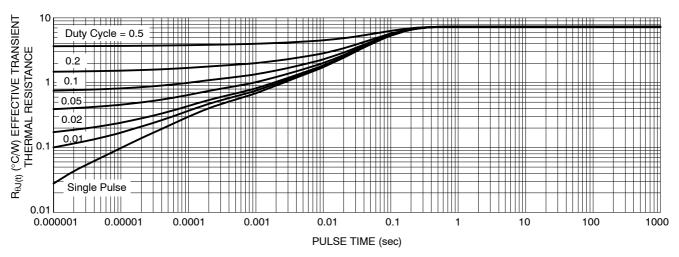
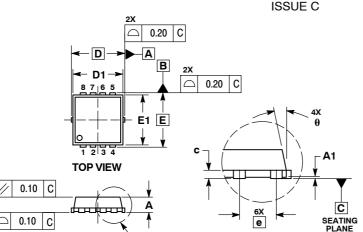


Figure 13. Thermal Response

PACKAGE DIMENSIONS

WDFN8 3.3x3.3, 0.65P CASE 511AB

DETAIL A



DETAIL A

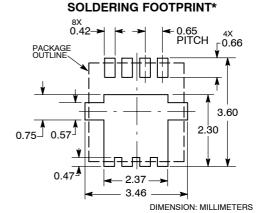
NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS			INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.70	0.75	0.80	0.028	0.030	0.031	
A1	0.00		0.05	0.000		0.002	
b	0.23	0.30	0.40	0.009	0.012	0.016	
С	0.15	0.20	0.25	0.006	0.008	0.010	
D		3.30 BSC		0.130 BSC			
D1	2.95	3.05	3.15	0.116	0.120	0.124	
D2	1.98	2.11	2.24	0.078	0.083	0.088	
E		3.30 BSC		0.130 BSC			
E1	2.95	3.05	3.15	0.116	0.120	0.124	
E2	1.47	1.60	1.73	0.058	0.063	0.068	
E3	0.23	0.30	0.40	0.009	0.012	0.016	
е	0.65 BSC			0.026 BSC			
G	0.30	0.41	0.51	0.012	0.016	0.020	
K	0.64			0.025			
L	0.30	0.43	0.56	0.012	0.017	0.022	
L1	0.06	0.13	0.20	0.002	0.005	0.008	
M	1.40	1.50	1.60	0.055	0.059	0.063	
θ	0°		12°	0°		12°	

0.10 С Α В \oplus 0.05 С e/2 ¥ E2 E3_ _\ D2 G-**BOTTOM VIEW**

SIDE VIEW



*For additional information on our Pb -Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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